Attorney's Docket No.: 12732-050002 / US4967D1

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Tatsuya Arao et al. Art Unit: Unknown Serial No.: New Divisional Application Examiner: Unknown

Filed : July 21, 2003

Title : METHOD OF MANUFACTURING SEMICONDUCTOR DEVICE

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT

Under 35 USC §120, this application relies on the earlier filing date of application serial number 09/873,334, filed on June 5, 2001. The attached list of references were submitted to and/or cited by the Office in the prior application and, therefore, are not provided in this application.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: July 21, 2003

John F. Hayden Reg. No. 37,640

Fish & Richardson P.C. 1425 K Street, N.W. 11th Floor Washington, DC 20005-3500

Telephone: (202) 783-5070 Facsimile: (202) 783-2331

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U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 12732-050002

Application No. New Divisional

Information Disclosure Statement by Applicant

(Use several sheets if necessary)

Applicant
Tatsuya Arao et al.

(37 CFR §1.98(b))

Filing Date
July 21, 2003

Group Art Unit

**Application** 

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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Other Documents (include Author, Title, Date, and Place of Publication)					
Examiner	Desig.				
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	AQ				
	AR				
	AS				
	AT				

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if n next communication to applicant.	ot in conformance and not considered. Include copy of this form with